

Title (en)

METHOD FOR DEPOSITING A SEMICONDUCTOR LAYER SYSTEM, WHICH CONTAINS GALLIUM AND INDIUM

Title (de)

VERFAHREN ZUM ABSCHEIDEN EINES HALBLEITER-SCHICHTSYSTEMS; WELCHES GALLIUM UND INDIUM ENTHÄLT

Title (fr)

PROCÉDÉ DE DÉPÔT D'UN SYSTÈME DE COUCHES SEMI-COCONDUCTRICES CONTENANT DU GALLIUM ET DE L'INDIUM

Publication

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Application

**EP 20725451 A 20200505**

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Abstract (en)

[origin: WO2020225228A1] The invention relates to a method for depositing a semiconductor layer system, wherein a first layer sequence has layers containing gallium and a second layer sequence has layers containing indium. In order to prevent gallium from being incorporated from residues in the process chamber into the layer containing indium when the layers containing indium are deposited, according to the invention a reactive gas containing indium is additionally supplied to the process chamber (2) during the first process step and the first process parameters (2) are adjusted such that the first layer or layer sequence (11) contains no indium or such that, in an intermediate step between the first and second process steps, a reactive gas containing indium is supplied to the process chamber (2) and in doing so the process parameters are adjusted such that no indium is deposited on the substrate (4), and, in the second process step, the second process parameters are adjusted such that the second layer contains no gallium.

IPC 8 full level

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